

<p>O.I.P.E.</p> <p>SCANNED <i>MS 4</i> G.A. <i>EW</i></p>	<p>PATENT DATE</p>
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APPLICATION NO. 09/925375	CONT/PRIOR F	CLASS 324	SUBCLASS 754	ART UNIT <del>2838</del>	EXAMINER <del>ME71A+116</del>
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## APPLICANTS

# TITLE

Semiconductor device testing apparatus and semiconductor device manufacturing method using it

PTO-2040  
12/89[illegible]

<input type="checkbox"/> <b>TERMINAL DISCLAIMER</b>	<b>DRAWINGS</b>		<b>CLAIMS ALLOWED</b>	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims
<input type="checkbox"/> The term of this patent subsequent to _____ (date) has been disclaimed.  <input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S. Patent. No. _____     	_____ (Assistant Examiner) (Date)		<b>NOTICE OF ALLOWANCE MAILED</b>	
	_____ (Primary Examiner) (Date)		<b>ISSUE FEE</b>	
Amount Due			Date Paid	
<input type="checkbox"/> The terminal _____ months of this patent have been disclaimed.	_____ (Legal Instruments Examiner) (Date)		<b>ISSUE BATCH NUMBER</b>	

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